

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of: **MEARS ET AL**.

Serial No. 10/603,621

) Examiner: H Jey TSAI

Confirmation No. 4467

) Art Unit: 2812

Filing Date: JUNE 26, 2003

Attorney Docket: 62604

For: METHODS OF FABRICATING SEMICONDUCTOR STRUCTURES HAVING
IMPROVED CONDUCTIVITY EFFECTIVE)

MASS

CITATION UNDER 37 CFR §1.97(c)

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Attached is a form PTO-1449 listing several references for consideration in the examination of the above-identified application. A copy of each reference is also enclosed. It is requested that these references be considered by the Examiner and officially made of record in accordance with the provisions of 37 CFR \$1.97 and Section 609 of the MPEP.

Respectfully submitted

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PATENT STATEMENT

Atty Docket: Serial No.: Applicant: Filing Date:

62604 10/603,621 MEARS

Group:

MEARS AUGUST 22, 2003 2812

	U.S. PATENT DOCUMENTS							
Examiner Initials		Document Number		Name	Class	Sub Class	Filing Date	
	AA	4,594,603	06/10/86	Holonyak, Jr.	357	16	01/24/85	
	AB	4,937,204	06/26/90	Ishibashi et al.	437	110	01/4/89	
	AC	4,969,031	11/06/90	Kobayashi et al.	357	63	02/3/83	
	AD	5,05,887	10/08/91	Yamazaki	357	4	01/18/90	
	AE	5,216,262	06/1/93	Tsu	257	17	03/2/92	
	AF	5,357,119	10/18/94	Wang et al.	257	18	02/19/93	
	AG	5,684,817	11/04/97	Houdre et al.	372	45	05/1/96	
	АН	5,683,934	11/4/03	Candelaria	437	134	05/3/96	
	Al	5,994,164	11/30/99	Fonash et al.	438	97	03/18/98	
	AJ	6,058,127	05/2/00	Joannopoulos et al.	372	92	12/12/97	
	AK	6,274,007	08/14/01	Smirnov et al.	204	192	03/14/00	
	AL	6,281,518	08/28/01	Sato	257	13	12/3/98	
	AM	6,281,532	08/28/01	Doyle et al.	257	288	06/28/99	
	AN	6,344,271	02/05/02	Yadav et al.	428	402	03/23/99	
	AO	6,472,685	10/29/02	Takagi	257	77	12/2/98	
	AP	6,498,359	12/24/02	Schmidt et al.	257	190	05/18/01	
	AQ	2003/ 0034529	02/20/03	Fitzgerald et al.	257	369	10/8/02	
	AR	2003/ 0057416	03/27/03	Currie et al.	257	19	09/20/02	
FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Sub Class	Translation	
	AS	02/103767	12/27/02	wo	H01L	21/20		
	AT	2,347,520	09/06/00	GB	G02B	5/18	<u> </u>	
	AU							

EXAMINER:	DATE CONSIDERED:

***EXAMINER**: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

RMATION DISCLOSURE STATEMENT

Atty Docket: Serial No.: Applicant:

62604 10/603,621 MEARS

Filing Date: Group: AUGUST 22, 2003

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ATENIA.		OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)
	AV	Xuan Luo et al.; "Chemical Design of Direct-Gap Light-Emitting Silicon", published July 25, 2002 by The American Physical Society; Vol. 89, Number 7
	AW	R. Tsu; University of North Carolina at Charlotte, "Phenomena in Silicon Nanostructure Devices"; published 09/06/2000 © Springer-Verlag 2000
	AX	P.D. Ye et al., "GaAs MOSFET with Oxide Gate Dielectric Grown by Atomic Layer Deposition"; © 2003 Agere Systems, March 2003
	AY	Novikov et al.; "Silicon-based Optoelectronics" © 1999-2003 by John Wiley & Sons, Inc.; pp/ 1-6
	AZ	
	ВА	
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	вк	
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